

## **Quarterly Reliability Monitoring Results**

## Quarters: Q3/2021 to Q4/2022

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs		User Part Number						
		PESD5V5HS2-SF						
		Part Description						
		NXP ICN8	8 Protection INDI					
		BD package						
Test		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
	TEST							
	Pre- and Post-Stress							
# 1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		MIL-STD-750-1						
	HTRB	M1038 Method A						
		Tj = Tjmax, Vr = 100% of max. datasheet						
# 5	Bias	reverse voltage	1000 hours	68	4040	0		
		JECD22 4404						
	TC	JESD22-A104						
# 7	Temperature Cycling	-40 °C to 125°C	1000 cycles	109	6440	0		
	UHAST	JESD22-A118						
# 8 <b>o</b> r	Unbiased HAST	Tamb = 130 °C, RH = 85 %						
# 6 01	Olibiased HAST		- 96 hours	n.a.	n.a.	n.a.		
	AC	JESD22-A102 Tamb = 121 °C, RH = 100 %						
	Autoclave	Pressure = 205 kPa (29.7 psia)						
# 8a	Autociave	Pressure = 203 KPa (29.7 psia)						
	HAST	JESD22-A110						
	Highly Accelerated Stress	Tamb = 130 °C, RH = 85%, VR = 80 % of						
# 9	Test	rated reverse voltage <sup>[1]</sup>	1000 hours	108	6400	0		
# 9		MIL-STD-750 Method 1037	1000 110013	100	0400	U		
	IOL	ton = toff, devices powered to insure $\Delta T_j$ =						
# 10	Intermittent Operating Life		1000					
# 10	Intermittent Operating Life	100 C for 15000 cycles	1000 hours	n.a.	n.a.	n.a.		
	RSH	JESD22-A111						
# 20	Resistance to Solder Heat	260 °C ± 5 °C	10 s	n.a.	n.a.	n.a.		
	SD							
# 21	Solderability	J-STD-002		18	180	0		

<sup>[1]</sup> The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test # 5) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
NXP ICN8	Protection INDI	4040	0	1,1	9,51E+08

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